

ICS 29.045
CCS H 80



**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 24579-2009

**Test method for measuring surface metal contamination of
polycrystalline silicon by acid extraction-atomic absorption
spectroscopy**

酸浸取 原子吸收光谱法测定多晶硅表面金属污染物

(English Translation)

Issued on: October 30, 2009

Implemented on: June 1, 2010

Issued by: Standardization Administration of China

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What this standard covers

This standard specifies the use of acid leaching from the surface of the polycrystalline silicon pieces of metal impurities. And graphite furnace atomic absorption quantitative detection of trace metal impurities on the polysilicon block surface analysis methods. This standard applies to the alkali metal, alkaline earth metal and the first series of transition elements such as sodium, zinc detection, Nickel, aluminum, iron, chromium. This standard applies to all kinds of rods, blocks, grain, sheet-shaped multi- product or single crystal silicon surface to detect metal contaminants. Since the block, pieces or grains of irregular shape. Area is difficult to accurately determine. Calculated according to the sample weight. Weight of the sample used is 50g ~ 300g, LOD tied to 0. 01ng/g.

Document data

International classification (ICS): 29.045.

Chinese classification (CCS): H80.

Estimated length of the Chinese original: 12,160 words.

Adopted international standard: SEMI MF1724-1104, MOD.

Standards quoted by this document

GB/T 11446.1; ISO 14644-1